



# LGE3M60065Q

## Silicon Carbide Power MOSFET



## Features

- High Blocking Voltage
- High Frequency Operation
- Low on-resistance
- Fast intrinsic diode with low reverse recovery

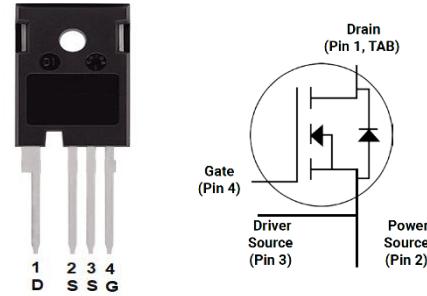
$V_{DS} = 650 \text{ V}$   
 $I_D@25^\circ\text{C} = 51\text{A}$   
 $R_{DS(\text{ON})} = 59\text{m}\Omega$

## Benefits

- Higher System Efficiency
- Parallel Device Convenience without thermal runaway
- High Temperature Application
- Hard Switching & Higher Reliability

## Applications

- Motor Drives
- Solar / Wind Inverters
- Onboard EV Charger
- AC/DC converters
- DC/DC converters
- Uninterruptable power supplies



**TO-247-4**  
**Pin definition**

Part Number	Package	Marking
LGE3M60065Q	TO-247-4	LGE3M60065Q

## Maximum Ratings ( $T_c=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test conditions	Value	Unit
Drain - Source Voltage	$V_{DS\text{max}}$	$V_{GS}=0\text{V}, I_D=100\mu\text{A}$	650	V
Gate - Source Voltage (dynamic)	$V_{GS\text{max}}$	AC ( $f>1 \text{ Hz}$ )	-8 / +23	V
Gate - Source Voltage (static)	$V_{GS\text{op}}$	static	-4 / +18	V
Continuous Drain Current	$I_D$	$V_{GS} = 18\text{V}, T_c=25^\circ\text{C}$ $V_{GS} = 18\text{V}, T_c=100^\circ\text{C}$	51 36	A
Pulsed Drain Current	$I_{D(\text{pulse})}$	$T_c=25^\circ\text{C}$	97	A
Short Circuit Capability	$t_{SC}$	$V_{DD}=400\text{V}, V_{GS}=18\text{V}$	9	$\mu\text{s}$
Short Circuit Capability	$I_{DS}$	$V_{DD}=400\text{V}, V_{GS}=18\text{V}$	300	A
Total power dissipation	$P_D$	$T_c=25^\circ\text{C}$	208	W
Operating Junction Temperature	$T_J$		-55 to 175	$^\circ\text{C}$
Storage Temperature	$T_{STG}$		-55 to 175	$^\circ\text{C}$

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handing procedures.



**Electrical Characteristics** ( $T_C=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0\text{V}, I_D = 100\mu\text{A}$	650			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 5\text{mA}$	1.9	2.7	3.9	V
		$V_{DS} = V_{GS}, I_D = 5\text{mA}, T_J = 150^\circ\text{C}$		2.0		V
		$V_{DS} = V_{GS}, I_D = 5\text{mA}, T_J = 175^\circ\text{C}$		1.9		V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 650\text{V}, V_{GS} = 0\text{V}$	0	1	100	$\mu\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = 18\text{V}, V_{DS} = 0\text{V}$	0	10	200	nA
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = -4\text{V}, V_{DS} = 0\text{V}$	-200	-10	0	nA
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	$V_{GS} = 16\text{V}, I_D = 15\text{ A}$		68		$\text{m}\Omega$
		$V_{GS} = 16\text{V}, I_D = 15\text{ A}, T_J = 150^\circ\text{C}$		68		
		$V_{GS} = 16\text{V}, I_D = 15\text{ A}, T_J = 175^\circ\text{C}$		72		
		$V_{GS} = 18\text{V}, I_D = 20\text{ A}$		59	75	
		$V_{GS} = 18\text{V}, I_D = 20\text{ A}, T_J = 150^\circ\text{C}$		64		
		$V_{GS} = 18\text{V}, I_D = 20\text{ A}, T_J = 175^\circ\text{C}$		68		
		$V_{DS} = 20\text{V}, I_D = 20\text{ A}, T_J = 150^\circ\text{C}$		11		
Transconductance	$g_{fs}$	$V_{DS} = 20\text{V}, I_D = 20\text{ A}, T_J = 175^\circ\text{C}$		10.7		S
		$V_{DS} = 20\text{V}, I_D = 20\text{ A}, T_J = 175^\circ\text{C}$		10.5		
		$V_{DS} = 20\text{V}, I_D = 20\text{ A}, T_J = 175^\circ\text{C}$				
Input capacitance	$C_{iss}$	$V_{DS} = 400\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$		1600		pF
Output capacitance	$C_{oss}$			145		
Reverse transfer capacitance	$C_{rss}$			11		
$C_{oss}$ Stored Energy	$E_{oss}$			14		
Total gate charge	$Q_g$	$V_{DS} = 400\text{V}, V_{GS} = -4\text{V} / 18\text{V}$ $I_D = 20\text{ A}$		78		nC
Gate-source charge	$Q_{gs}$			21		
Gate-drain charge	$Q_{gd}$			34		
Internal gate input resistance	$R_{g(\text{int})}$	$f = 1\text{MHz}, I_D = 0\text{A}$		2.1		$\Omega$
Turn-On Switching Energy	$E_{ON}$	$V_{DS} = 400\text{ V}, V_{GS} = -4\text{V}/18\text{V}$ $I_D = 20\text{A}, R_{G(\text{ext})} = 2\Omega$ , $L = 200\mu\text{H}$		15		$\mu\text{J}$
Turn-Off Switching Energy	$E_{OFF}$			12		
Turn-On Delay Time	$t_{d(on)}$			10		
Rise Time	$t_r$			8		
Turn-Off Delay Time	$t_{d(off)}$			19		
Fall Time	$t_f$			5		
Avalanche Capability	$E_{AS}$	$V_{DD} = 100\text{V}, V_{GS}=20\text{V}, L=1\text{mH}$		200		mJ
Avalanche Capability	$I_{AV}$			20		A

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**LGE3M60065Q**  
Silicon Carbide Power MOSFET



**Reverse Diode Characteristics** ( $T_C=25^\circ C$  unless otherwise specified)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Diode Forward Voltage	$V_{SD}$	$V_{GS} = -4V, I_{SD} = 10A,$		3.9		V
		$V_{GS} = -4V, I_{SD} = 10A, T_J = 150^\circ C$		3.5		
		$V_{GS} = -4V, I_{SD} = 10A, T_J = 175^\circ C$		3.4		
Continuous Diode Forward Current	$I_S$	$V_{GS} = -4V$		35		A
Reverse Recovery time	$t_{rr}$	$V_{GS} = -4V, I_{SD} = 20A,$ $V_R = 400V, dI/dt = 2000 A/\mu s$		20		ns
Reverse Recovery Charge	$Q_{rr}$			160		nC
Peak Reverse Recovery Current	$I_{rrm}$			14		A

**Thermal Characteristics**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Thermal Resistance (per device)	$R_{th(j-c)}$	junction-case		0.6	0.72	°C/W

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<http://www.lgesemi.com>



## Typical Performance

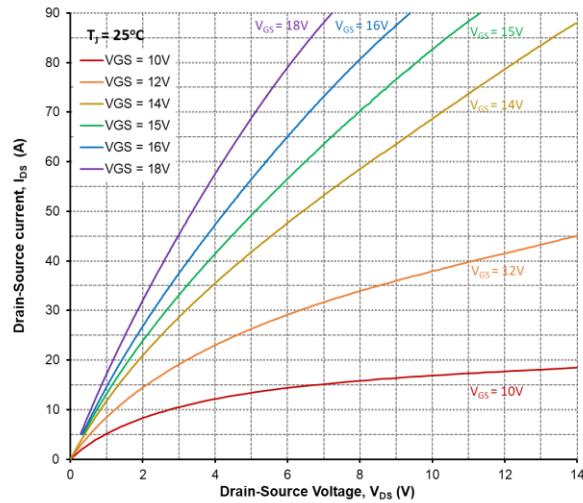


Figure 1. Output Characteristics,  $T_J = 25^\circ\text{C}$

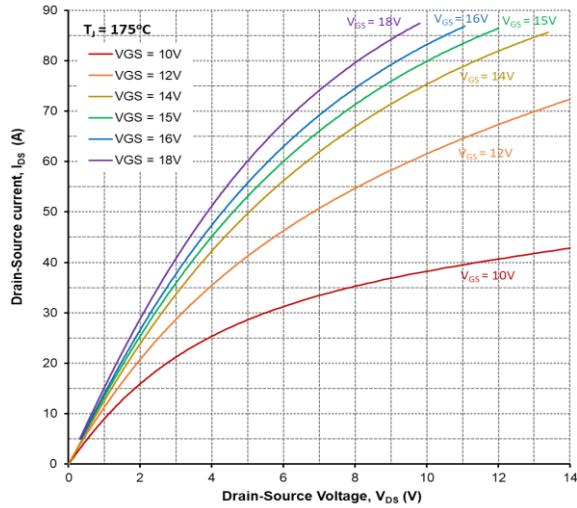


Figure 2. Output Characteristics,  $T_J = 175^\circ\text{C}$

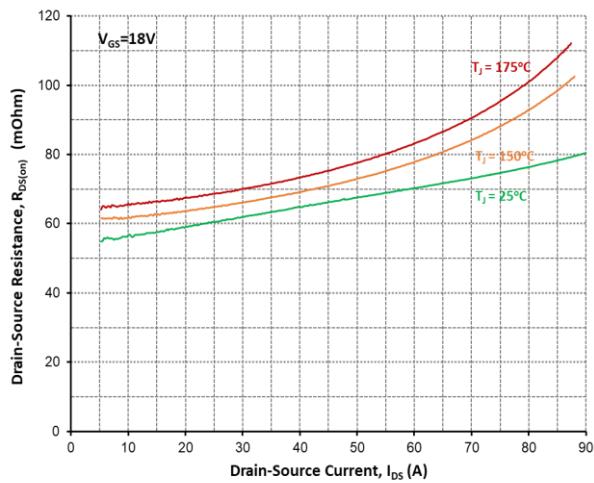


Figure 3. On-Resistance vs. Drain Current  
For Various Temperatures

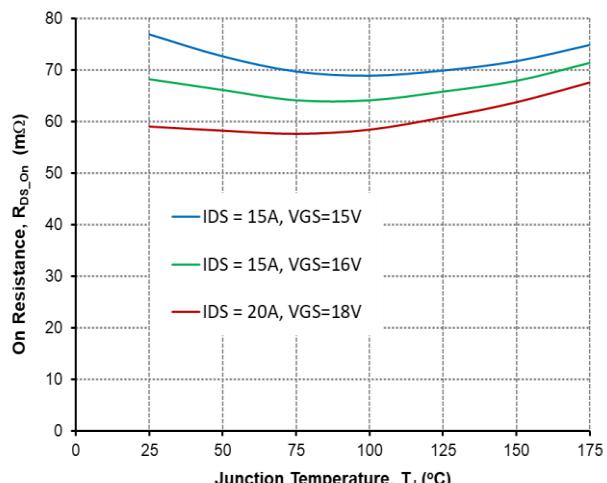


Figure 4. On-Resistance vs. Temperature

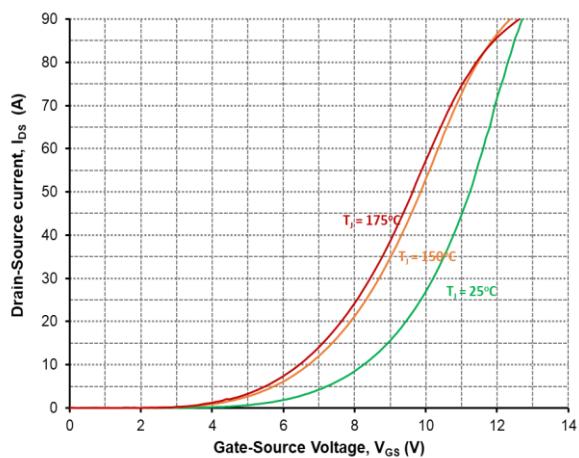


Figure 5. Transfer Characteristic For Various Junction  
Temperatures

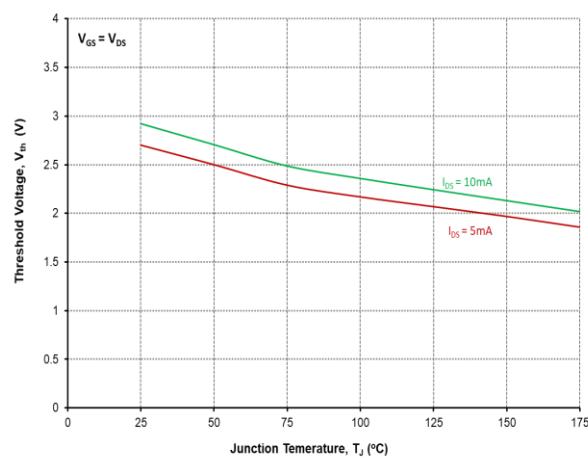


Figure 6. Threshold Voltage vs. Temperature

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handling procedures.



## Typical Performance

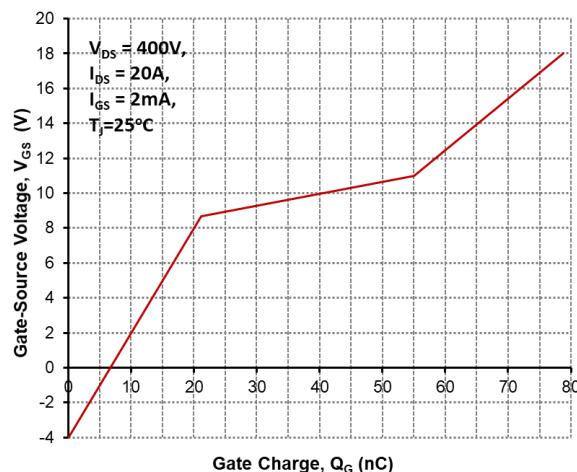


Figure 7. Gate Charge Characteristics

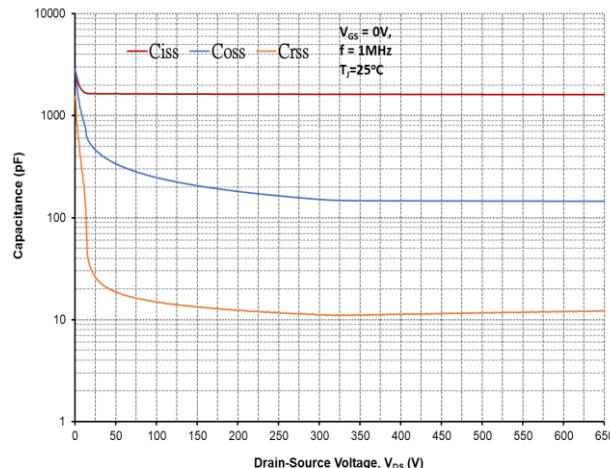


Figure 8. Capacitances vs. Drain-Source Voltage (0-650V)

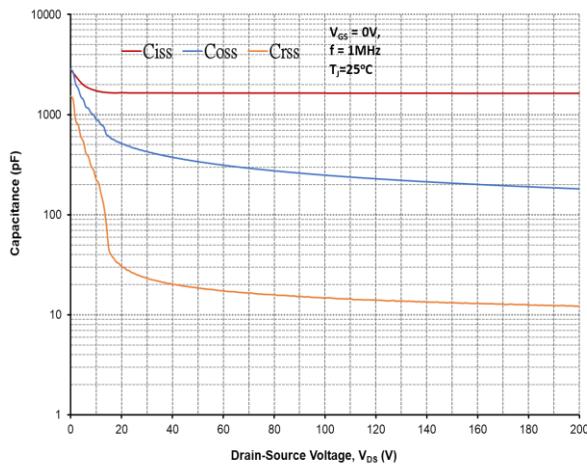


Figure 9. Capacitances vs. Drain-Source Voltage (0-200V)

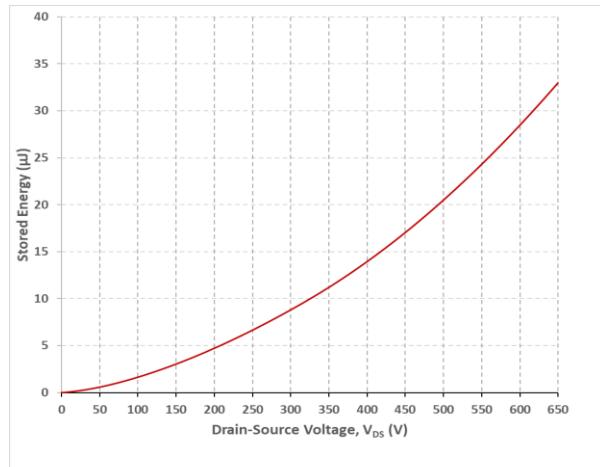


Figure 10. Output Capacitor Stored Energy

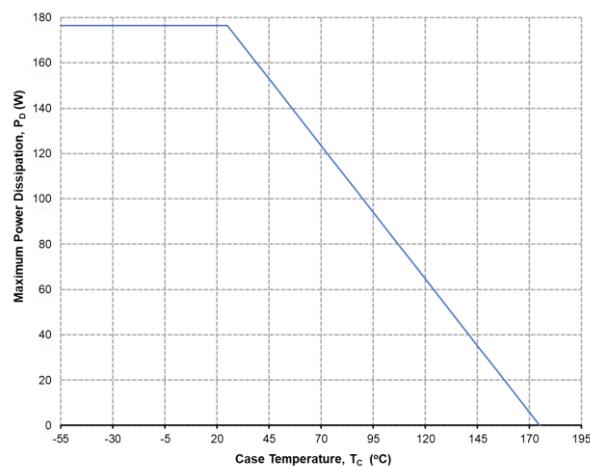


Figure 11. Maximum Power Dissipation Derating vs. Case Temperature

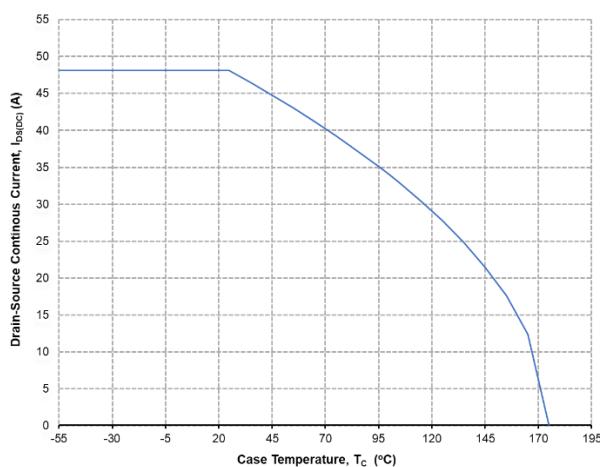


Figure 12. Continuous Drain Current Derating vs. Case Temperature

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## Typical Performance

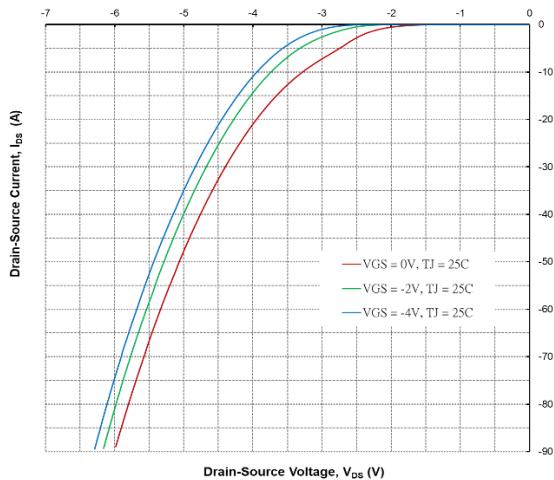


Figure 13. Body Diode Characteristics @ 25°C

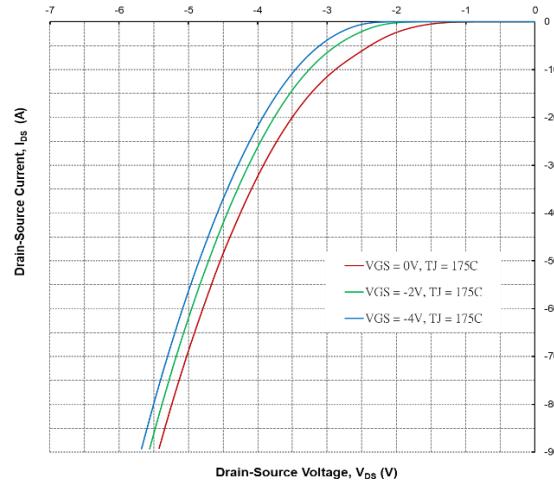


Figure 14. Body Diode Characteristics @ 175°C

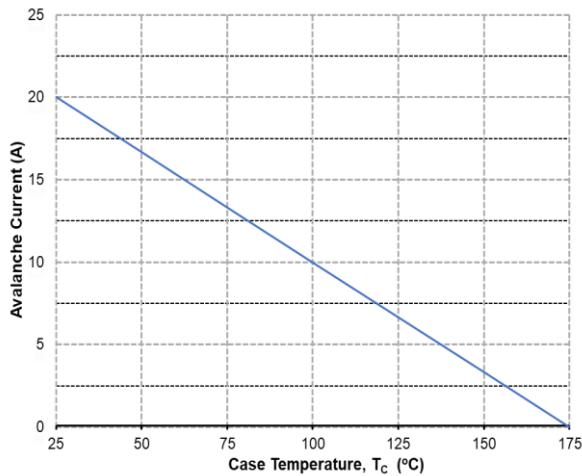


Figure 15. Single Avalanche vs. Temperature

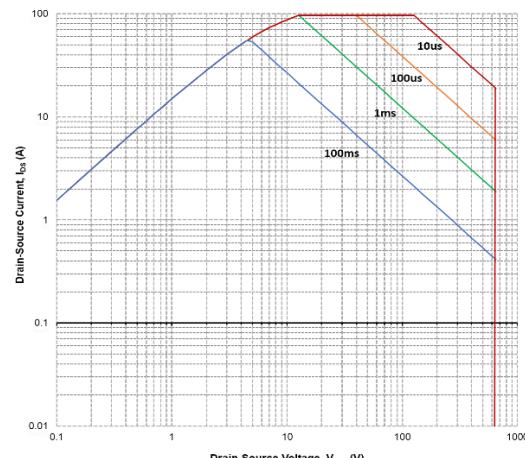
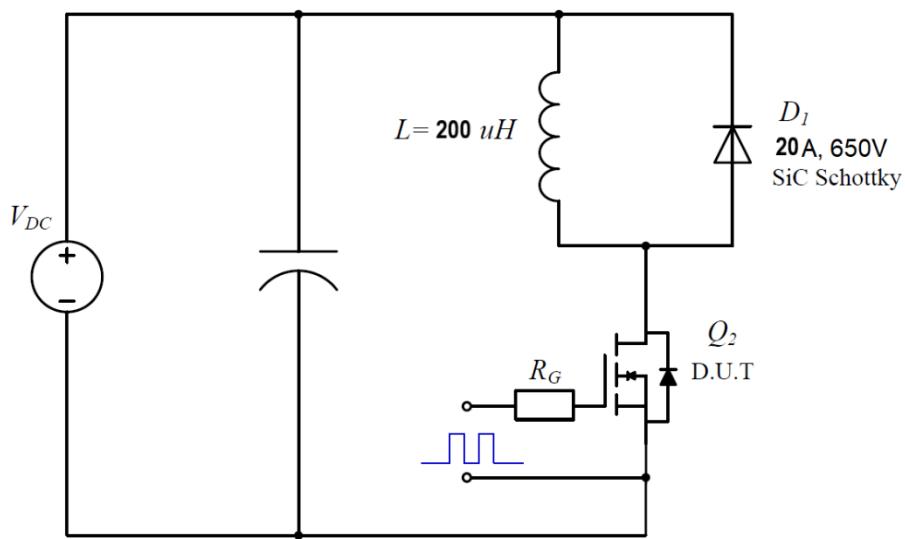
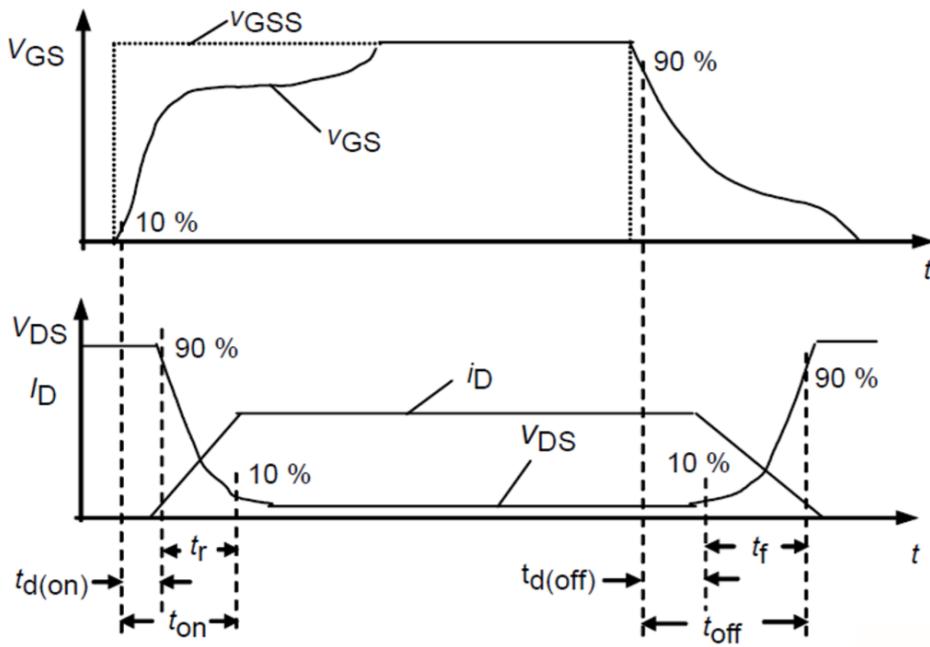


Figure 16. Safe Operating Area

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handing procedures.



## Switching Times Definition and Test Circuit

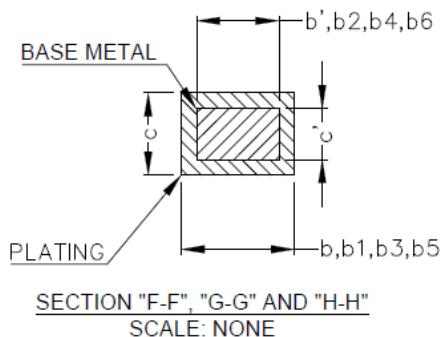
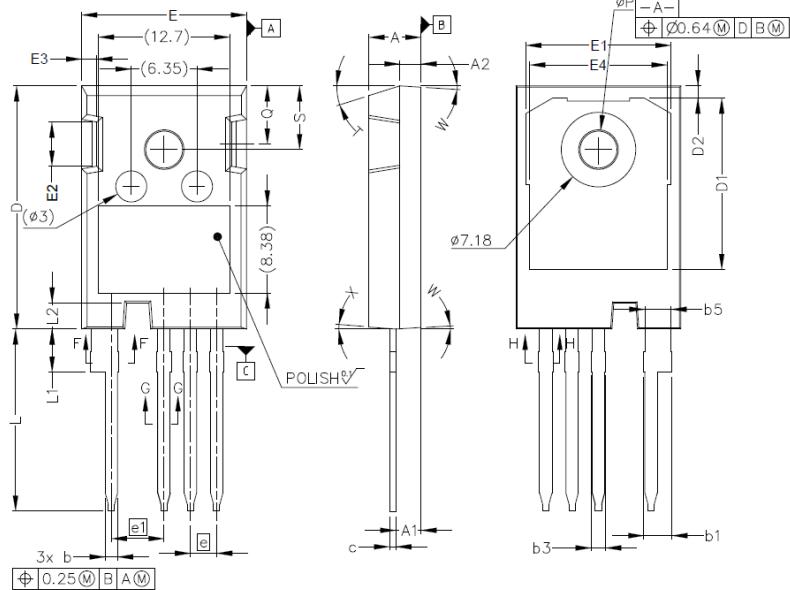


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## Package Dimensions

(TO-247-4 Package)



SYMBOL	MILLIMETERS	
	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b'	1.07	1.28
b	1.07	1.33
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
c'	0.55	0.65
c	0.55	0.68
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54 BSC	
e1	5.08 BSC	
N	4	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
oP	3.51	3.65
Q	5.49	6.00
S	6.04	6.30
T	17.5° REF.	
W	3.5 ° REF.	
X	4 ° REF.	

Packge	Packing	Box Size L×W×H(mm)	Quatity(pcs/box)	Carton Size L×W×H(mm)	Quatity(pcs/carton)
TO-247	30pcs/Tube	570×155×50	450	580×340×125	1800

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